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Notice of References Cited				Applicat	Application/Control No. 09/863,044		Applicant(s)/Patent Under Reexamination ICHIOKA ET AL.	
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				U.S. PATENT DO	CUMENTS	<u> </u>		
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			.!	FOREIGN PATENT I	DOCUMENTS			
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name		Classification	
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